



#### **General Description**

The AOZ8350DI-04 is a 1-channel unidirectional high surge transient voltage suppressor designed to protect power rails such as battery and Vbus from damaging ESD or surge events.

This device consists of a unidirectional TVS diode in a single package. During transient events, the diode directs the transient to either the positive side of the power supply line or to ground.

The AOZ8350DI-04 provides a typical line-to-ground capacitance of 1200 pF and low clamping voltage making it ideally suited for power rail protection in mobile and computing devices.

The AOZ8350DI-04 comes in a RoHS compliant and Halogen Free 2.0 mm x 1.25 mm x 0.5 mm package and is rated for -40°C to +125°C junction temperature range.

#### Features

- ESD protection for high-speed data lines:
  - IEC 61000-4-2 (ESD immunity):
    - Air discharge: ±30 kV
    - Contact discharge: ±30 kV
  - IEC61000-4-5 (Lightning, 8/20 µs): 160 A
- Capacitance between I/O to GND: 1200 pF
- Low clamping voltage
- Reverse Working Voltage: 4.8 V

#### Applications

- Battery
- Mobile devices
- Notebook computers



## **Typical Application**



## **Pin Configuration**



DFN2.0x1.25\_2L



#### **Ordering Information**

Part Number	Ambient Temperature Range	Package	Environmental
AOZ8350DI-04	-40°C to +125°C	DFN2x1.25-2L	Green Product



AOS Green Products use reduced levels of Halogens, and are also RoHS compliant. Please visit www.aosmd.com/media/AOSGreenPolicy.pdf for additional information.

#### **Absolute Maximum Ratings**

Exceeding the Absolute Maximum ratings may damage the device.

Parameter	Rating
Storage Temperature (T <sub>S</sub> )	-65°C to +150°C
ESD Rating per IEC61000-4-2, contact <sup>(1)</sup>	±30kV
ESD Rating per IEC61000-4-2, air <sup>(1)</sup>	±30kV
8/20µs Surge IEC61000-4-5	±160A

#### Notes:

1. IEC 61000-4-2 discharge with C\_{Discharge} = 150pF, R\_Discharge = 330 $\Omega$ .

2. Human Body Discharge per MIL-STD-883, Method 3015  $C_{\text{Discharge}}$  = 100pF,  $R_{\text{Discharge}}$  = 1.5k $\Omega$ .

### **Maximum Operating Ratings**

Parameter	Rating
Junction Temperature (T <sub>J</sub> )	-40°C to +125°C



### **Electrical Characteristics**

 $T_A = 25^{\circ}C$  unless otherwise specified.



Symbol	Parameter	Condition	Min.	Тур.	Max.	Units
V <sub>RWM</sub>	Reverse Working Voltage				4.8	V
V <sub>BR</sub>	Reverse Breakdown Voltage	I <sub>T</sub> = 1mA	6	7	8.5	V
I <sub>R</sub>	Reverse Leakage Current	V <sub>T</sub> =Max. V <sub>RWM</sub>		0.1	0.5	μA
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 15mA		0.85		V
		I <sub>PP</sub> = 1A		7.5	8.5	V
V <sub>CL</sub>	Clamping Voltage <sup>(0)</sup>	I <sub>PP</sub> = 100A		12	13.5	V
		I <sub>PP</sub> = 160A		14	15.5	V
R <sub>DNY</sub>	Dynamic Resistance <sup>(3)</sup>	I <sub>PP</sub> = 1A to 160A		0.04		Ω
CJ	Junction Capacitance	V <sub>I/O</sub> = 0V, f = 1MHz,		1200		pF

#### Note:

3. These specifications are guaranteed by design and characterization.



# **Typical Characteristics**



# Package Dimensions, DFN2.0x1.25-2L, EP2\_S



**Top View** 



**Bottom View** 





Side View

**RECOMMEND LAND PATTERN** 

CVA ID OL C	DIMENSIO	NS IN MILL	IMETERS	DIMEN	DIMENSIONS IN INCHES				
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX			
A	0.450	0.500	0.550	0.0177	0.0197	0.0217			
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020			
b	0.950	1.000	1.050	0.0374	0.0394	0.0413			
с	0	.152REF	7	0.0060REF					
D	1.900	2.000	2.100	0.0748	0.0787	0.0827			
e	1	.035BSC	2	0.0407BSC					
Е	1.200	1.250	1.300	0.0472	0.0492	0.0512			
L	0.980	1.030	1.080	0.0386	0.0406	0.0425			
L1	0	.100REF	7	0	.0039RE	F			
L2	0	.130REF	7	0	.0051RE	F			
L3	0.450	0.500	0.550	0.0177	0.0197	0.0217			
h	0	.120REF	7	0.0047REF					

NOTE

1. ALL DIMENSIONS ARE IN MILL IMETERS.

2. DIMENSIONS ARE INCLUSIVE OF PLATING.

3. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6MIL EACH.

4. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

5. PADDLE EXPOSED ON BOTTOM.

## Tape and Reel Dimensions, DFN2.0x1.25-2L, EP2\_S

#### Carrier Tape





UNIT: MM

PACKAGE	A0	BO	K0	DO	D1	E	E1	E2	PO	P1	P2	Т
DFN2.0×1.25	1.61 ±0.05	2.21 ±0.05	0.70 ±0.05	Ø1.50 +0.10 -0.00	Ø0.60 ±0.05	8.00 +0.3 -0.1	1.75 ±0.1	3.50 ±0.05	4.00 ±0.1	4.0 ±0.10	2.0 ±0.05	0.23 ±0.02

Σ

REEL







UNIT: MM

TAPE SIZE	REEL SIZE	М	Ν	W	Н	S
8	Ø180	Ø180.0 ±1.0	Ø54.4 ±1.0	8.60 +1.00 -0.00	Ø13.0 +0.5 -0.2	2,00 +0,5 -0.0

TAPE

Leader / Trailer & Orientation

3000pcs

Unit Per Reel:

 Image: Components tape
 Image: Components tape

 Components tape
 Image: Components tape

 Solomm MIN.
 Image: Components tape



## Part Marking



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#### LIFE SUPPORT POLICY

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As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user. 2. A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



4. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

5. PADDLE EXPOSED ON BOTTOM.



DFN2.0x1.25\_2L\_EP2\_S Tape and Reel Data

## DFN2.0x1.25 2L EP2 S Carrier Tape





UNIT: MM

PACKAGE	AO	BO	K0	DO	D1	E	E1	E5	PO	P1	Ρ2	Т
DFN2.0×1.25	1.61 ±0.05	2.21 ±0.05	0.70 ±0.05	Ø1.50 +0.10 -0.00	Ø0.60 ±0.05	8.00 +0.3 -0.1	1.75 ±0.1	3.50 ±0.05	4.00 ±0.1	4.0 ±0.10	2.0 ±0.05	0.23 ±0.02

# DFN2.0x1.25 2L EP2 S REEL







#### UNIT: MM

TAPE SIZE	REEL SIZE	М	Ν	W	Н	S
8	Ø180	Ø180.0 ±1.0	ø54.4 ±1.0	8.60 +1.00 -0.00	Ø13.0 +0.5 -0.2	2.00 +0.5 -0.0

#### DFN2.0x1.25\_2L\_EP2\_S\_TAPE





# AOS Semiconductor Product Reliability Report

# AOZ8350DI-04, rev A

**Plastic Encapsulated Device** 

**ALPHA & OMEGA Semiconductor, Inc** 

www.aosmd.com

Feb, 2020



This AOS product reliability report summarizes the qualification result for AOZ8350DI-04. Accelerated environmental tests are performed on a specific sample size, and then followed by electrical test at end point. Review of final electrical test result confirms that AOZ8350DI-04 passes AOS quality and reliability requirements. The released product will be categorized by the process family and be routine monitored for continuously improving the product quality.

Test Item	Test Condition	Time Point	Total Sample Size	Number of Failures	Reference Standard
HTRB	Temp = 150°C, Vdd=100% of VRWMmax	168 / 500 / 1000 hours	231 pcs	0	JESD22-A108
Precondition (Note A)	168hr 85°C / 85%RH + 3 cycle reflow@260°C	-	693 pcs	0	JESD22-A113
HAST	130°C , 85%RH, 33.3 psia, Vdd = 80% of VRWMmax	96 hours	231 pcs	0	JESD22-A110
Autoclave	121°C , 29.7psia, RH=100%	96 hours	231 pcs	0	JESD22-A102
Temperature Cycle	-65°C to 150°C, air to air	250 / 500 cycles	231 pcs	0	JESD22-A104

# I. Reliability Stress Test Summary and Results

**Note:** The reliability data presents total of available generic data up to the published date. Note A: MSL (Moisture Sensitivity Level) 1 based on J-STD-020

# II. Reliability Evaluation

## FIT rate (per billion): 15.26 MTTF = 7480 years

The presentation of FIT rate for the individual product reliability is restricted by the actual burn-in sample size. Failure Rate Determination is based on JEDEC Standard JESD 85. FIT means one failure per billion hours.

Failure Rate =  $Chi^2 \times 10^9 / [2 (N) (H) (Af)] = 15.26$ MTTF =  $10^9 / FIT = 7480$  years

**Chi**<sup>2</sup> = Chi Squared Distribution, determined by the number of failures and confidence interval  $\mathbf{N}$  = Total Number of units from burn-in tests

**H** = Duration of burn-in testing

**Af** = Acceleration Factor from Test to Use Conditions (Ea = 0.7eV and Tuse =  $55^{\circ}C$ ) Acceleration Factor [**Af**] = **Exp** [Ea / k (1/Tj u - 1/Tj s)]

Acceleration	Acceleration Factor ratio list:											
	55 deg C	70 deg C	85 deg C	100 deg C	115 deg C	130 deg C	150 deg C					
Af	259	87	32	13	5.64	2.59	1					

**Tj s** = Stressed junction temperature in degree (Kelvin), K = C+273.16

Tj u =The use junction temperature in degree (Kelvin), K = C+273.16

 $\mathbf{k}$  = Boltzmann's constant, 8.617164 X 10<sup>-5</sup>eV / K